

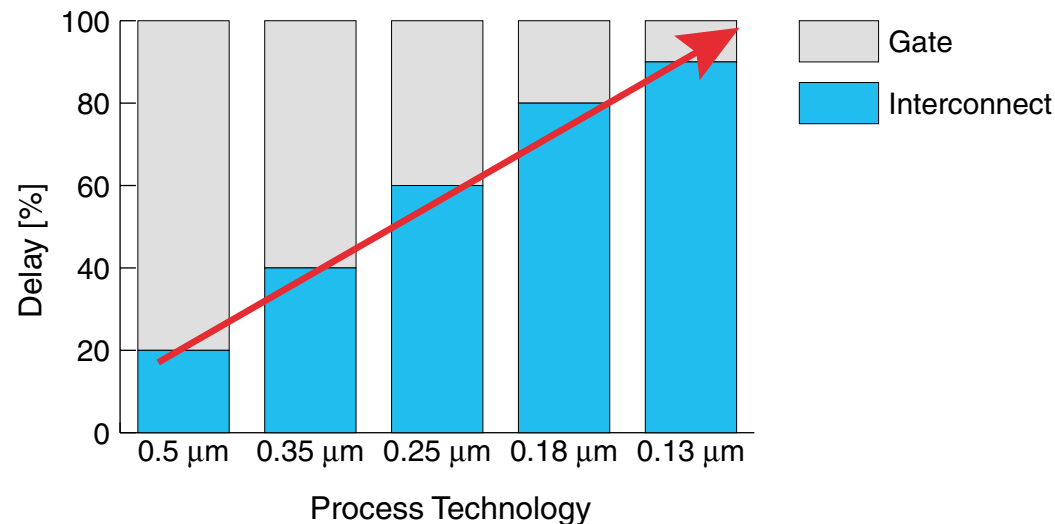


presents

***High-Speed High-Accuracy
3D VLSI Extraction***

■ Interconnects Now Dominate VLSI

- Timing
- Signal Integrity



■ Existing Interconnect Extractors **Fail**

- Poor Accuracy & High Speed
- Medium Accuracy & Very Low Speed

■ Need High-Speed High-Accuracy Extractor

- **Company**
- **Technology**
 - High-speed High-accuracy BEM 3D Field Solver
 - Efficient Net-by-Net RC Extraction
- **Products**
 - Extraction of Critical Cells, Blocks, Nets
 - Distributed RC Models
 - IR drop
 - Substrate Coupling
- **Differentiation**
 - 2D / 2.5D / 3D Tools
- **Summary**

■ History

- Privately held, located in San Francisco CA
- Founded in July 1996 by 3D Field Solver & MEMS experts
- DARPA contract to develop extremely fast & easy-to-use 3D CAD for MEMS

■ Products

- First MEMS product AutoMEMS® announced July 1998
- First VLSI product AutoIC® announced June 1999
- New Tools
 - AutoIC® v2, AutoIC-SMP™, AutoNet™, AutoSubstrate™, AutoIRdrop™, AutoMEMS® v2

■ Customers

- End-users include Siemens, Monterey, Analog Devices, Motorola, Texas Instruments, Hewlett-Packard, Sandia, MIT, Berkeley, CMU
- OEM licenses include Monterey Design

Company Mission



■ VLSI

Provide premium high-speed high-accuracy solutions for extraction, timing, and signal integrity problems for modern VLSI designs.

■ MEMS

Provide premium high-speed high-accuracy analysis of large, realistic MEMS devices.

■ Technology

- | | |
|----------------------|---|
| ● AutoBEM | Fastest BEM field solver |
| ● AutoBEM-SMP | Exploit fine-grained parallelism on SMP computers |

■ VLSI

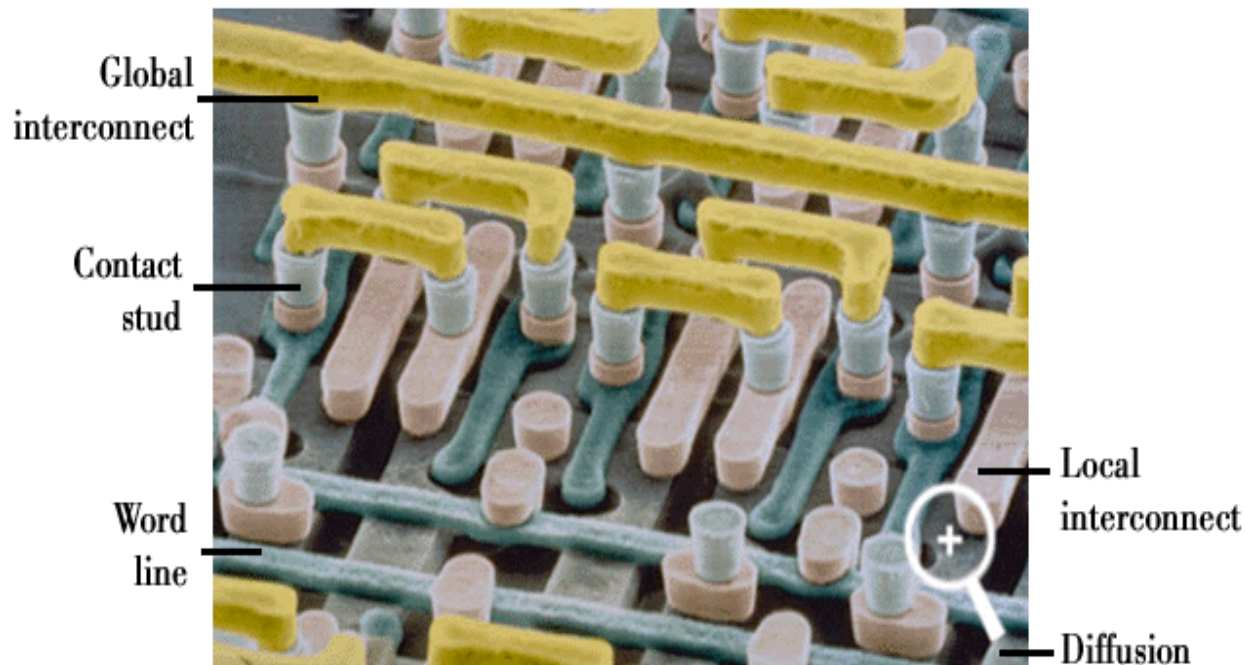
- | | |
|------------------------|---|
| ● AutoIC | Capacitance extraction of interconnects |
| ● AutoIC-SMP | SMP support |
| ● AutoNet | Distributed RC models from layout |
| ● AutoSubstrate | Resistive coupling in substrate |
| ● AutoIRdrop | Potential drop in powergrid |

■ MEMS

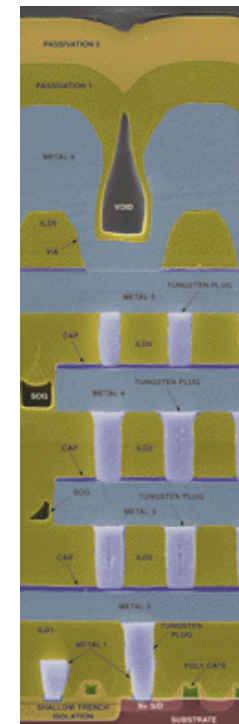
- | | |
|-----------------------|--------------------------------------|
| ● AutoMEMS | Coupled electro/mechanical simulator |
| ● AutoMEMS-SMP | SMP support |

VLSI Geometries

- Interconnects dominate performance
- Deep submicron is 3D
 - Huge layouts
 - Intricate topologies



- IBM



- AMD

■ RC Interconnect Extraction Tools

- High-Speed
- High-Throughput
- High-Capacity
- High-Accuracy

■ Possible Alternatives

● 3D Field Solvers

- Coyote Systems
- Raphael™
- FastCap

● Statistical Methods

- QuickCap™

● Pattern Matchers

- Simplex
- Frequency
- Mentor
- Ultima

■ Identify Advantages/Disadvantages

Pattern Matchers

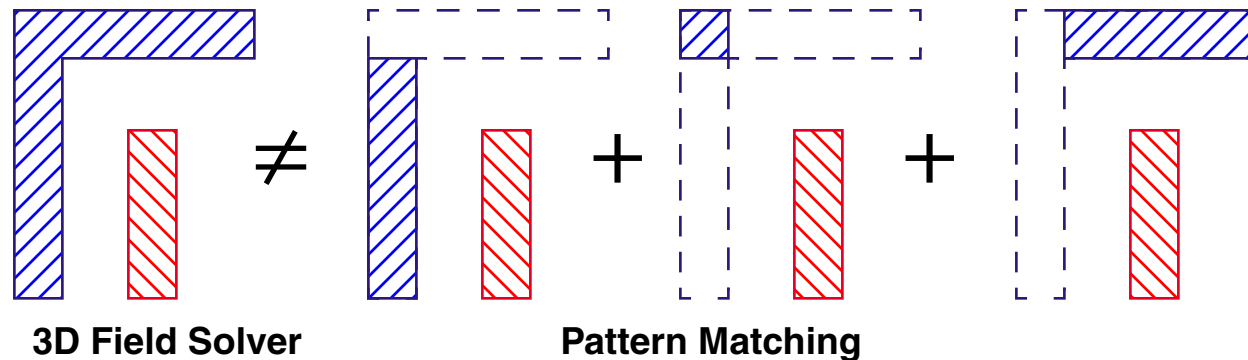


- **Why they are used**
 - Mature technology, Very Fast
 - Requires 3D field solver to develop pattern library

- **2D/2.5D tools do not capture 3D DSM effects**
 - Fast (<100,000 nets/hour) after lengthy precharacterization (100-200 hours)
 - Increasing difficulties with modern processes
 - Many Layers, small feature sizes
 - Arbitrary angles & non-manhattan geometries
 - PCB-style variable wire width
 - Increasing number of patterns needed
 - Optimistic “error cancellation” - no bounded errors
 - Large errors (>20%)

Accuracy Problem!

- Some pattern matching vendors claim $\ll 10\%$ errors
- Simple counterexample...



- **3D simulation reveals 20% errors using superpositioning!**
- Geometric non-linearities prevent accurate solutions

- **Why are they sometimes used**
 - **Alternative to FEM, FDM**
 - **Reasonably good for Self-Cap & Small Problems**

- **Why will they not solve the problem**
 - **No Distributed R's & C's**
 - **Very long run times with increasing number of nets**
 - **Inaccurate Coupling Capacitance - Cij**
 - **Only supports Manhattan Geometries**
 - **Expensive support for multiple dielectrics**
 - **Solves only part of the problem - Cii**

Alternative Solvers

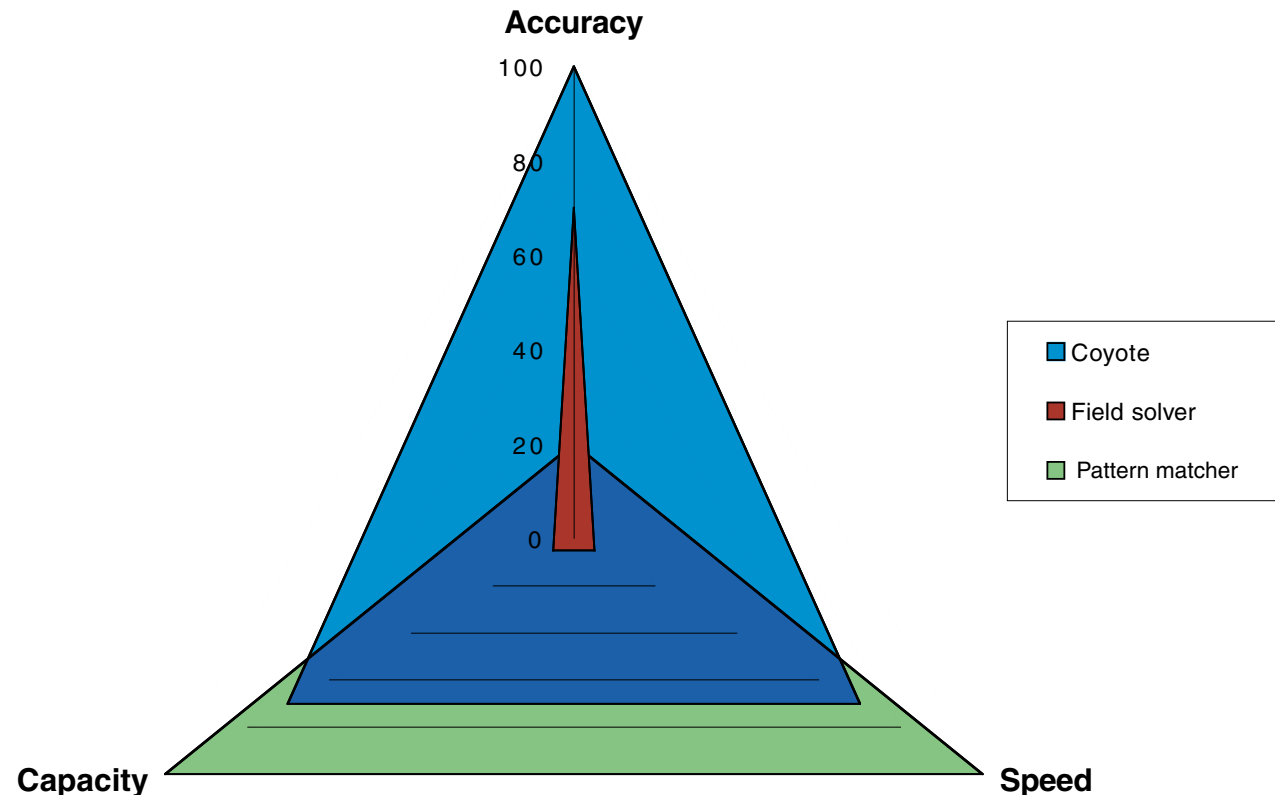
- **Proposed Technologies**
 - FEM
 - FDM
 - Traditional BEM

- **Why will they not solve the problem**
 - Not fast enough
 - Limited to very small problems
 - Huge memory and CPU time requirements

- **Computationally not feasible**

VLSI Extraction

- Coyote combines advantages of all approaches!
 - Field solver **accuracy**
 - Pattern matcher **speed & capacity**

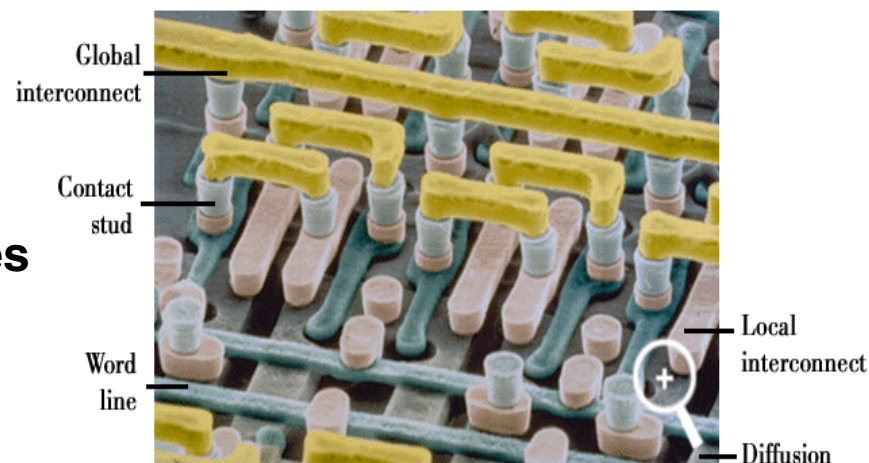


VLSI Geometries

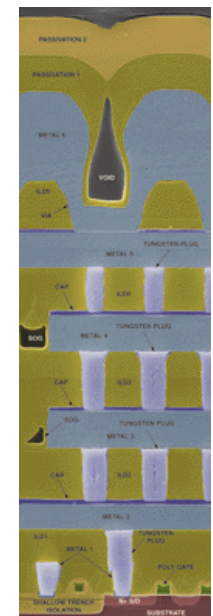
- Interconnects dominate performance
- Deep submicron is 3D

- High aspect ratios
- Extreme Density
- Round Corners
- Cylindrical Vias
- Variable width wires
- Nonideal Cross-Sections

● IBM



● AMD



- Coyote can verify the effect of all these features!
 - Simplex, Frequency, Avanti, Mentor, QuickCap™ cannot

- 3D problems require 3D solutions!

3D Field Solvers



- **Arbitrary Geometries**
 - PCB-style, manhattan & non-manhattan

- **Arbitrary Materials**
 - Planar & conformal dielectrics

- **Arbitrary Boundary Conditions**
 - Neumann, Dirichlet, mixed, floating

- **Only Coyote's AutoIC® solves everything!**
 - AutoIC is faster, more accurate, and easier to use!

3D Field Solvers

- If field solver, then pick **best** field solver
 - Simplest, smallest model
 - Most accurate (states & gradients)
 - Fastest runtime
 - Lowest memory requirements

	<i>BEM</i>			<i>FEM</i>	
	<i>Direct</i>	<i>Iterative</i>	<i>Multipole</i>	<i>Direct</i>	<i>Iterative</i>
Nr. nodes	N^2	N^2	N^2	N^3	N^3
Memory	N^4	N^4	$(N \log N)^2$	N^6	$N^{4.5}$
CPUtime	N^6	N^4	$(N \log N)^2$	N^9	$N^{4.5}$

- Coyote uses **Multipole Accelerated BEM**
- Computational Scaling $N^2 \rightarrow N \log N$

■ **VLSI Interconnect Extraction**

- **Accelerated Boundary Element Method**
- **Automatic meshed 3D model from 2D layout**
- **Adaptive mesh refinement**
- **Robust automation**
- **Scriptable batch-mode or interactive GUI-mode operation**
- **Superset of Sematech extraction API**
- **Cluster & symmetric multiprocessing (SMP) support**

AutoIC Speed



■ AutoIC™ 3D Field Solver

- 2,000,000 BEM elements/hour per cpu
- 1,500 nets/hour per cpu (user selected <2% error)

■ AutoIC vs. Field Solvers

- 10-50x faster than QuickCap™
- 100-500x faster than Raphael™

■ AutoIC vs. Library-based "Pattern Matchers"

- Similar speed to Frequency

◆ Accuracy

- +2.93% to -4.93% with no outliers

◆ Performance

- Full accuracy / GDS mode : 500 nets /hour:
- Full accuracy / LEF- DEF mode : 2500 nets/hour
- "-fast" option (+/- 15% accuracy) : 6500 nets/hour

— 5 — 5/26/99 Copyright © 1999 by Frequency Technology, Inc. All rights reserved.

The Frequency Technology logo, which includes the text "FREQUENCY TECHNOLOGY" and a stylized waveform icon.

■ Best Performance

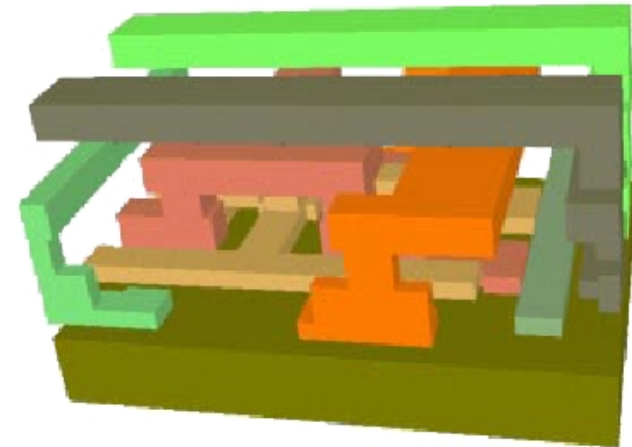
- Faster than FastCap, QuickCap™, Raphael™, Space, etc.
- As fast as pattern matchers!
- Solves many more problems
- Large savings replacing multiple licenses
- Large engineering time savings

■ Motorola SRAM Evaluation

- Self-cap Extraction
- Cross-cap Extraction
- Convergence
- Time & Memory
- Model Generation
- Ease-of-Use

■ Motorola Compared

- AutoIC™
- QuickCap™
- Raphael™



Motorola SRAM Cell

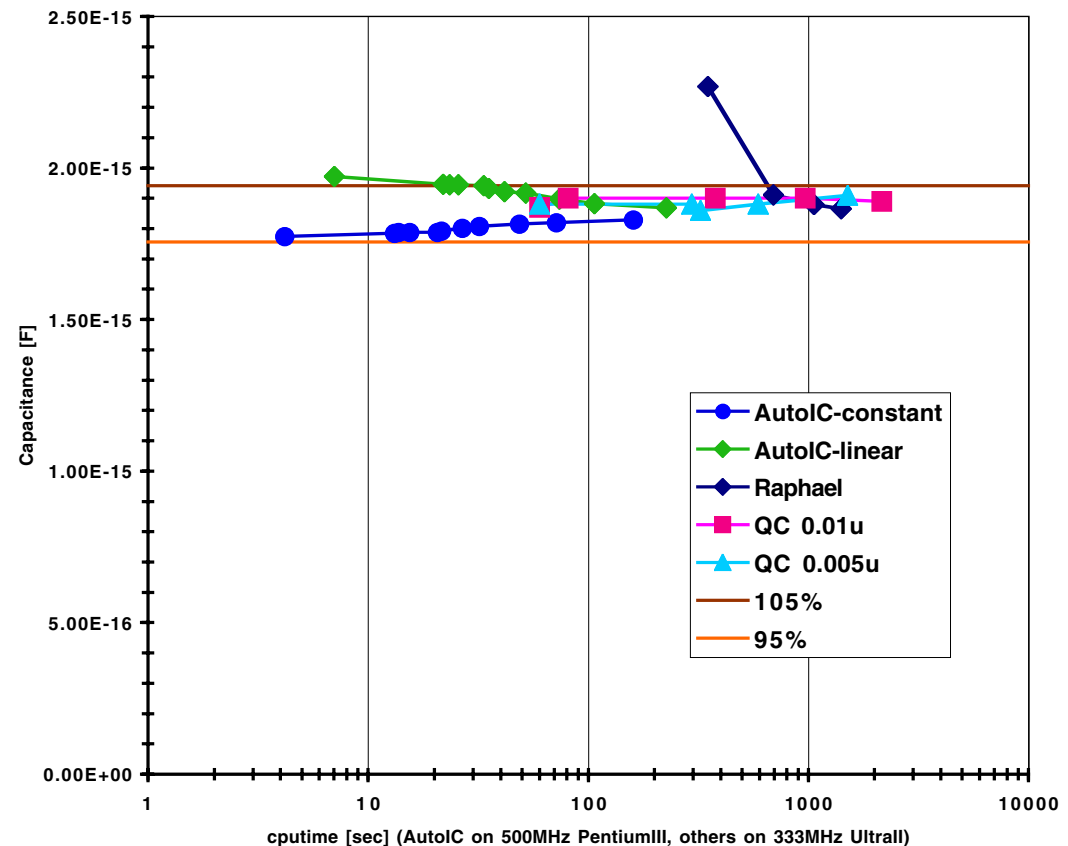


■ Convergence of bit-line self-capacitance

- Require better than $\pm 5\%$ accuracy

■ AutoIC

- 10-100x faster!
- Best convergence!
- Tight error bounds!

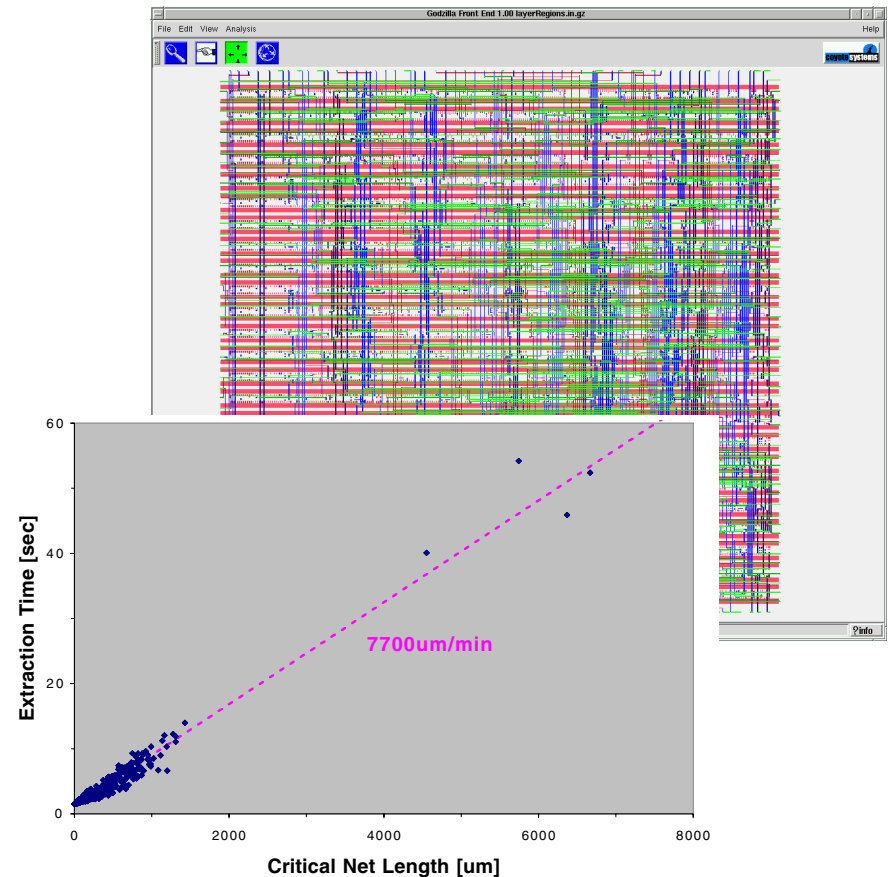


■ Extract Critical Nets

- 500 nets
- 1x1mm die
- 0.35um process
- 3 metal layers
- Multiple dielectrics

■ AutoIC results

- <2% Errors
- Excellent scaling
- 8mm/min extraction
- All nets extracted in 20 min using 1 cpu = 1,500 nets/hour
- All nets extracted in 1 min using 20 cpus = 30k nets/hour



- **Industry Std Layout**
 - GDSII, annotated GDSII, CIF, Sematech API

- **3D Model Generator**
 - Flexible process descriptor
 - API-mode or Batch-mode or GUI-mode

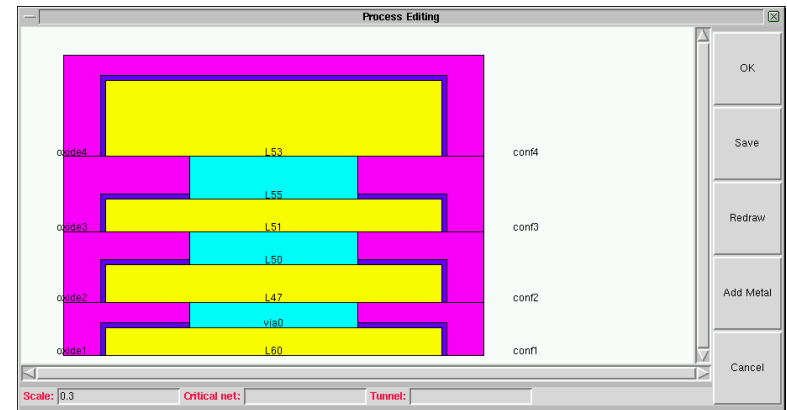
- **3D RC Extraction**
 - Lumped, distributed
 - API-mode or Batch-mode or GUI-mode

- **Industry Std Output**
 - Spice, Sematech API
 - 3D visualization

Model Generation

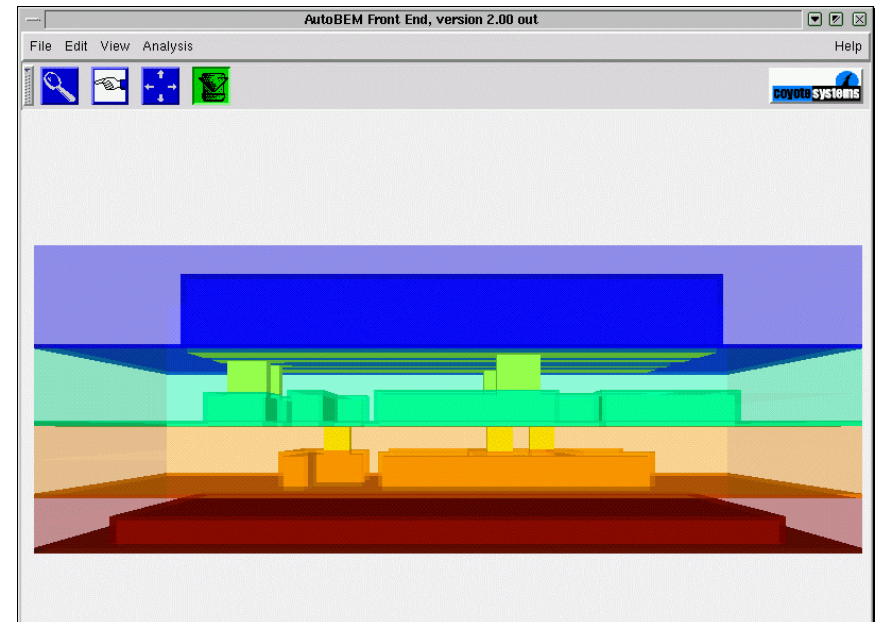
■ Input

- Layout
- Process Description
 - Arbitrary layers
 - Interlayer dielectrics
 - Conformal dielectrics



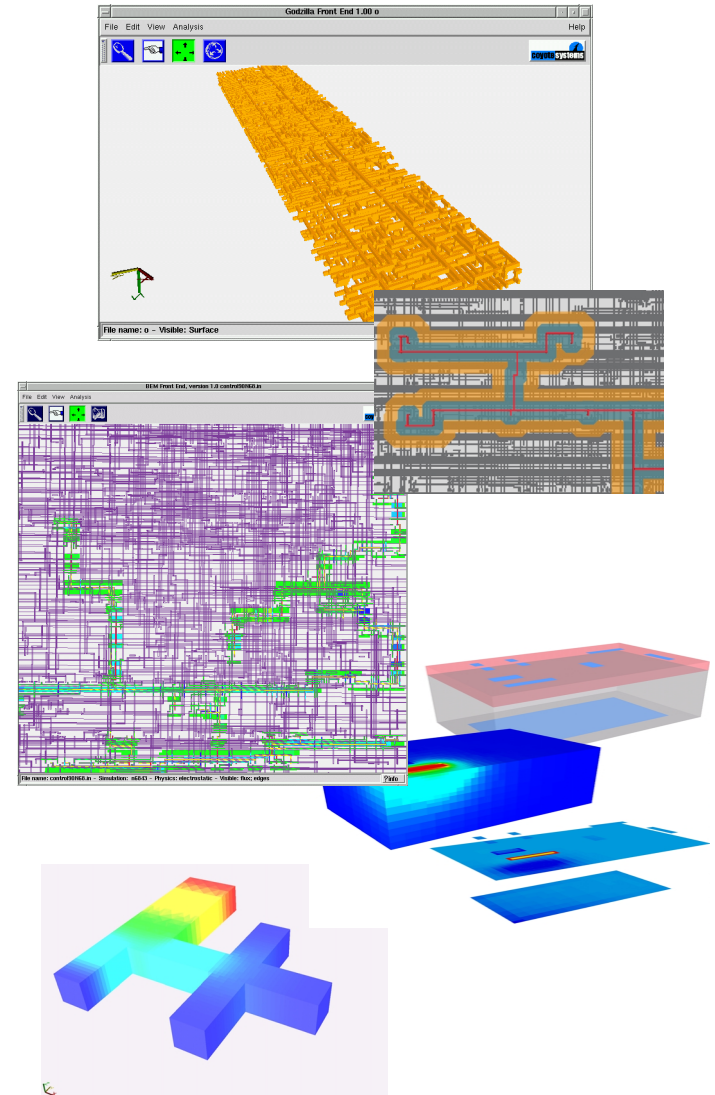
■ Output

- Meshed 3D Model



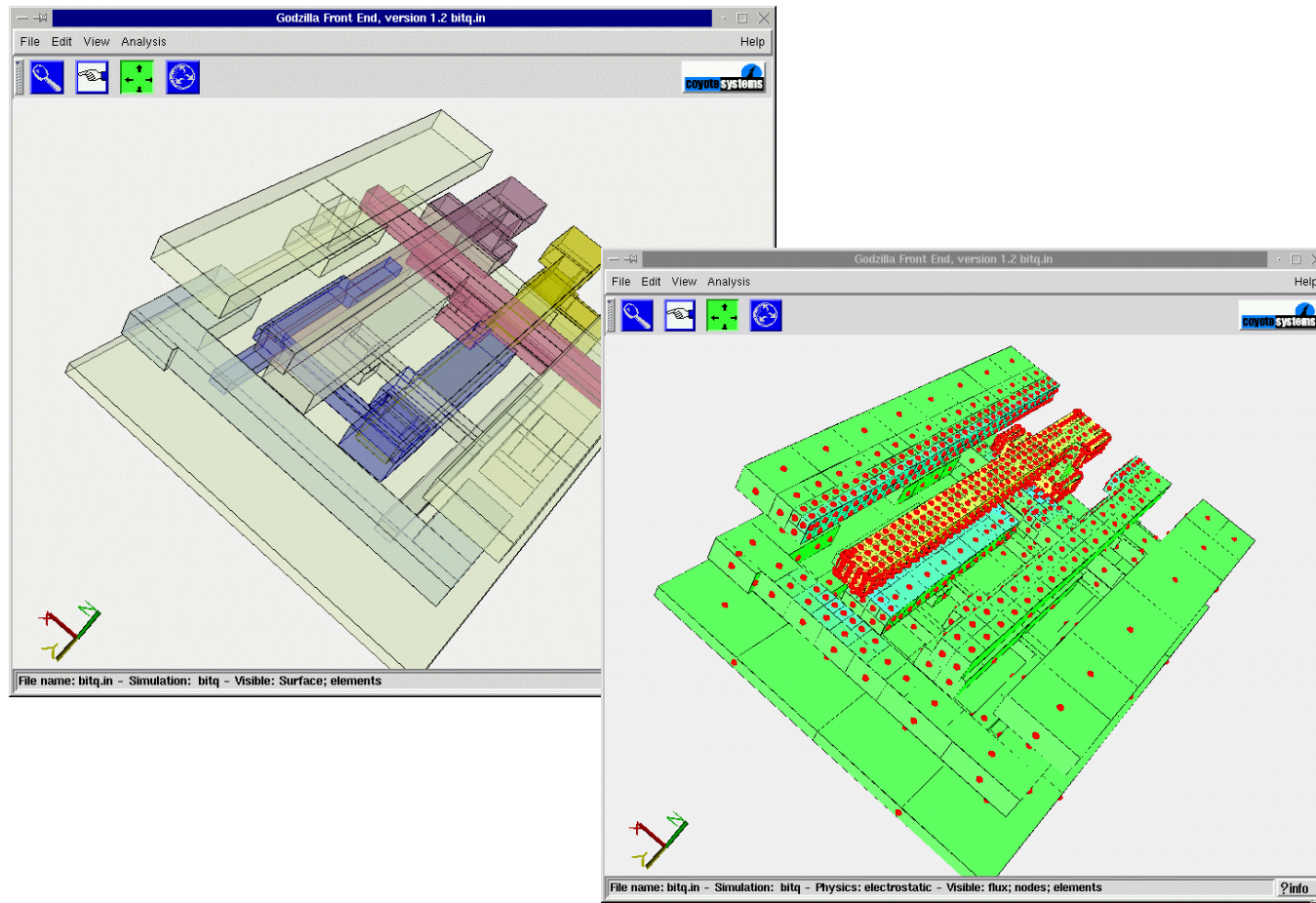
Applications

- **Critical Cells**
 - Coefficient generation
 - Cell optimization
- **Critical Blocks**
 - IP characterization
 - Routing
- **Critical Nets**
 - Clock trees, control lines
 - User-selected nets
- **Substrate Coupling**
- **IR drop**
 - Power grid effects delays



Critical Cells

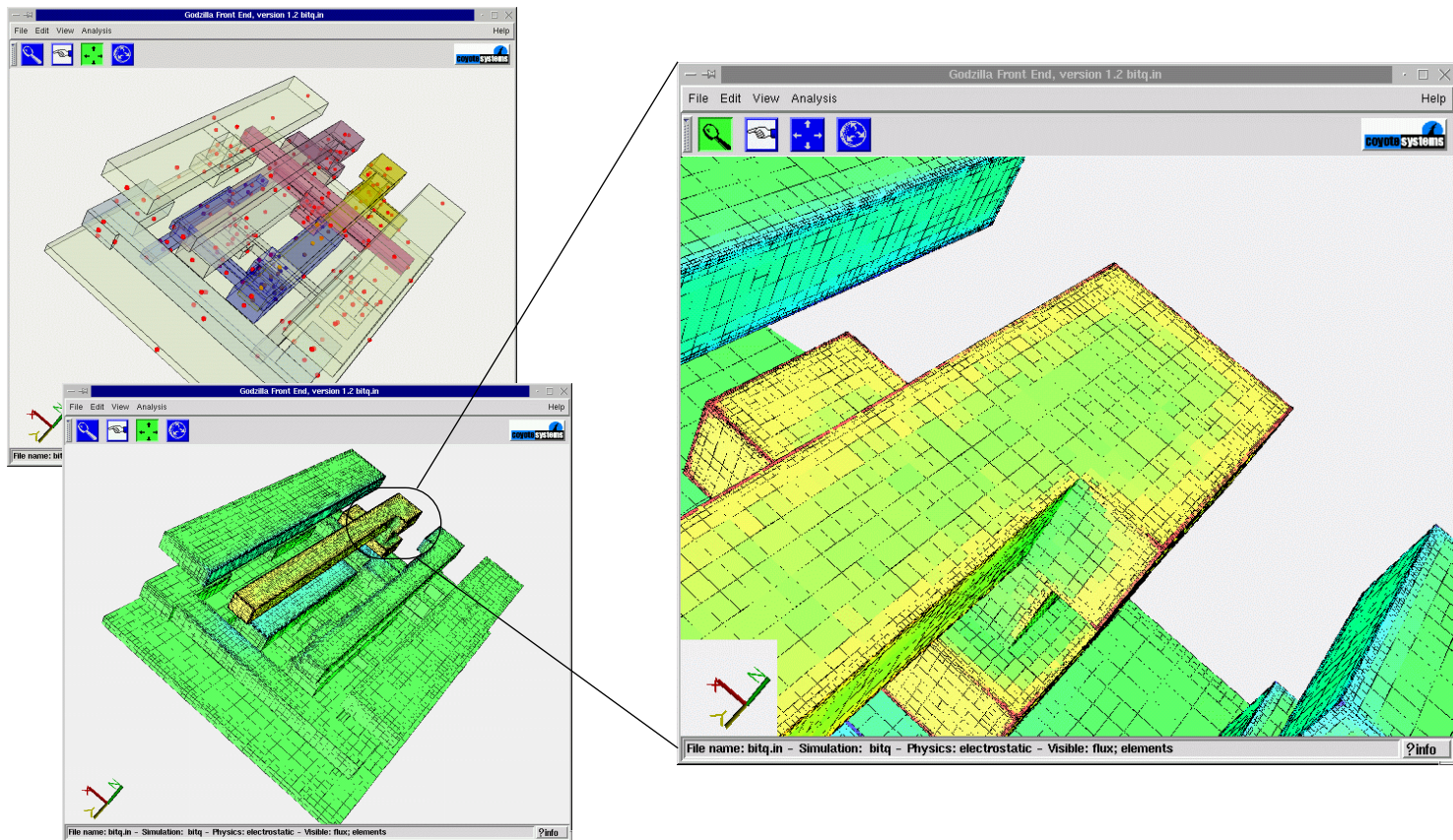
- AutoIC simulates 10,000 cells in 2 hours
 - 1 AutoIC license replaces 50-200 Raphael™ licenses



- Adaptive meshing on SRAM bit-line shown

Cell Optimization

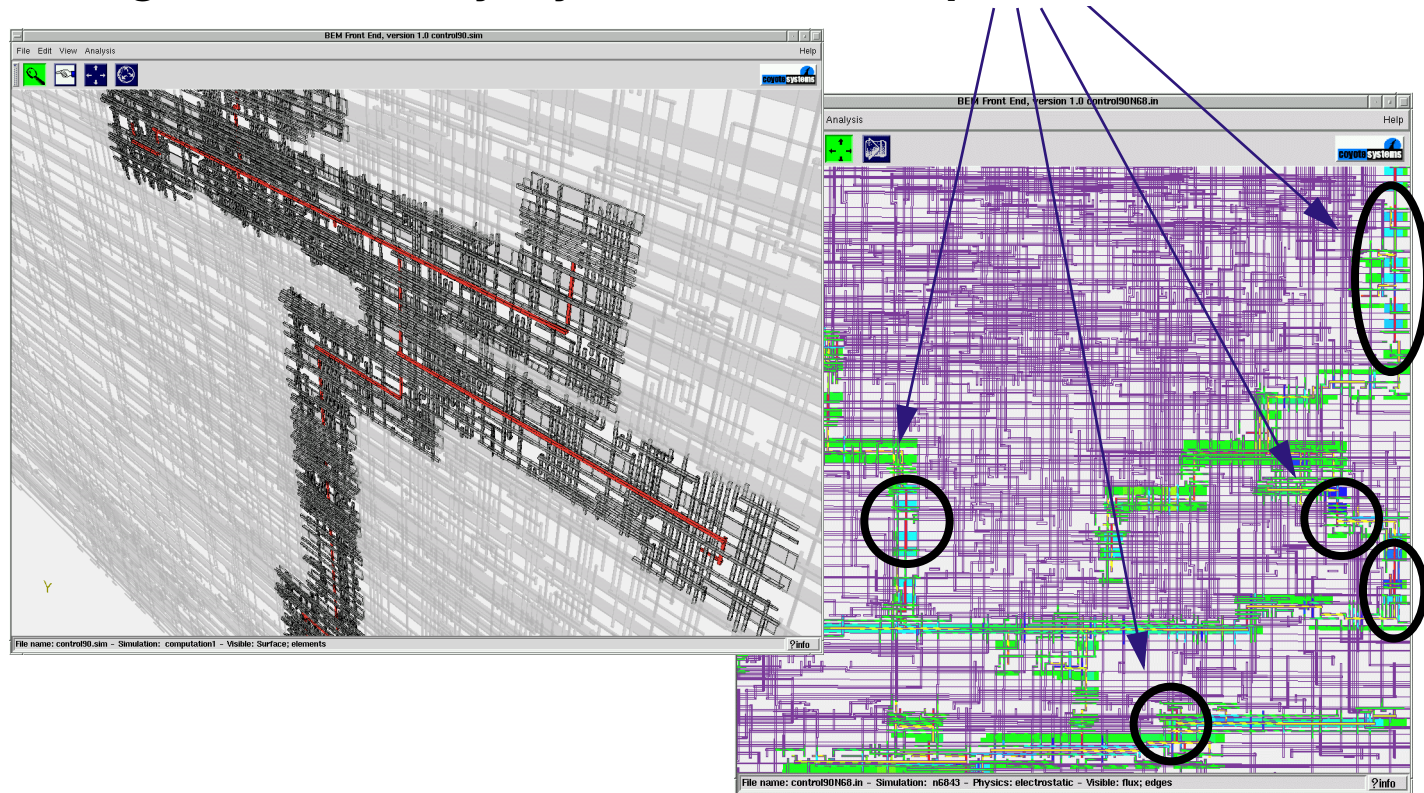
- AutoIC identifies where interactions occur
- Modify layout to optimize performance



- Magnitude of electrostatic flux on SRAM bit-line shown

Critical Nets

- Handles largest global nets
 - Automatic tunneling around **aggressor** net
 - 3D visualization **indicates** crosstalk areas
 - Designer can modify layout to **eliminate** problem

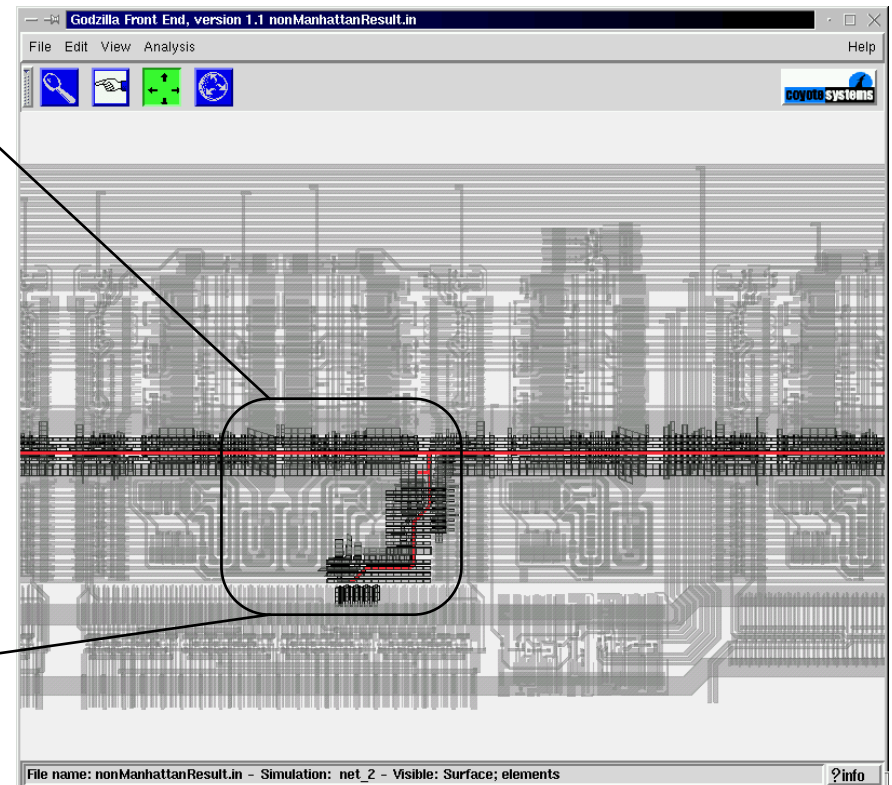
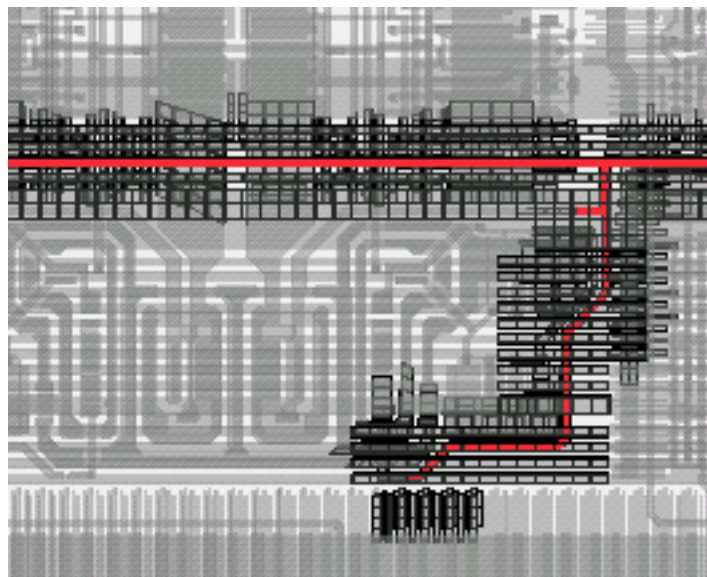


- 1 AutoIC license replaces 10-50 QuickCap™ licenses

Critical Blocks

■ PCB-style layout (Cypress)

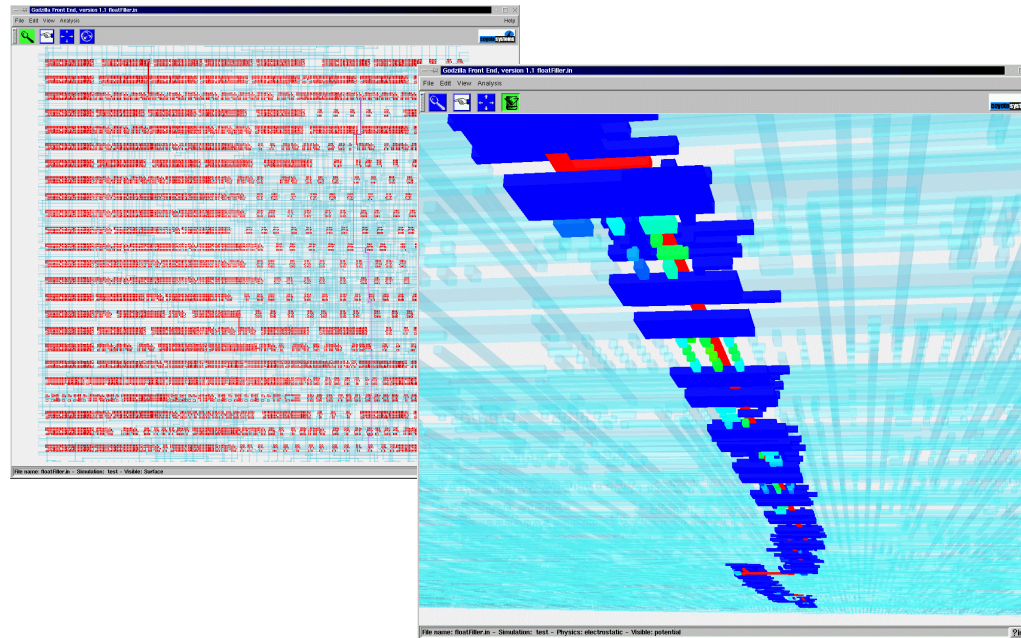
- Non-manhattan Geometries
- Varying Linewidths
- AutoIC 500x faster than QuickCap™!



- Aggressor net, 3D tunnel & 3D mesh shown

Non-Ideal Fabrication

- **AutoIC simulates Process Variations**
 - Any geometry
 - Any material
- **AutoIC correctly solves floating filler metal**
 - Note that filler adds 20% to self-cap!



- **Non-zero potential on floating filler shown**

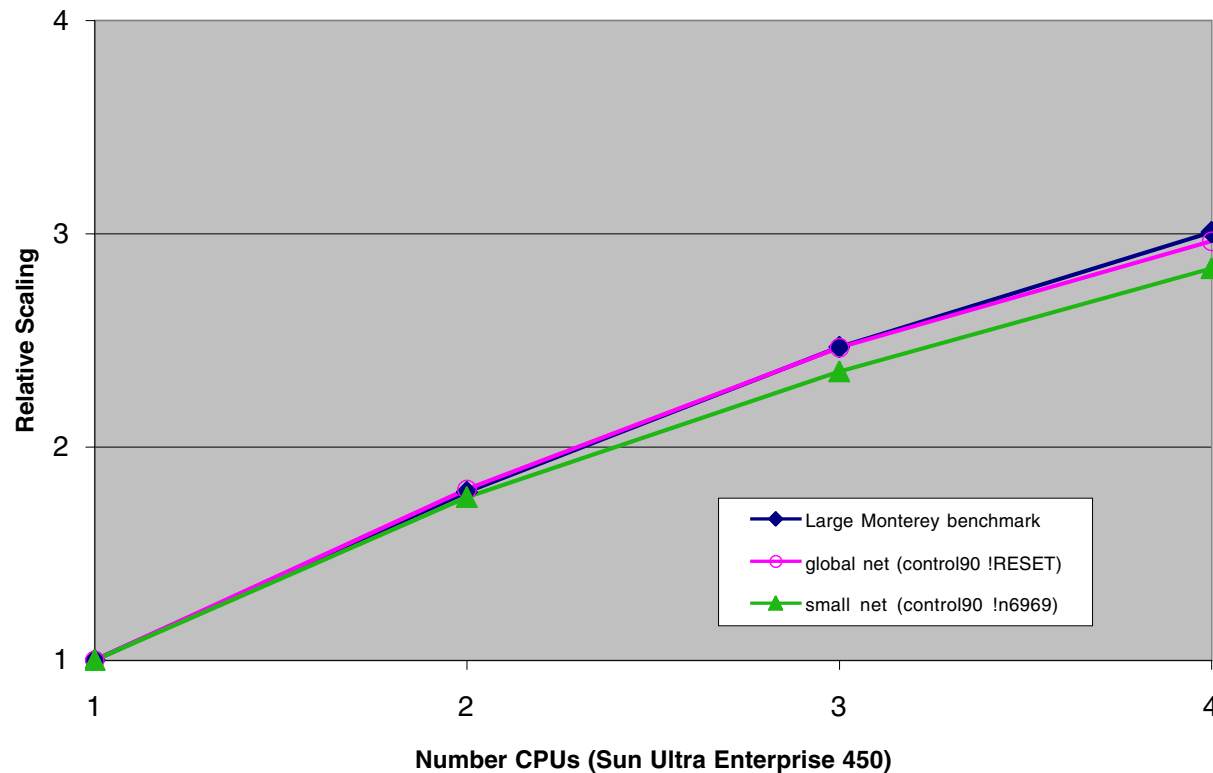
AutoIC-SMP Scaling



■ Symmetric multiprocessing support

- Excellent scaling with every added CPU
- Accelerates both large and small nets

SMP Scaling for Critical Net Extraction



"The Layout is the Design"



■ Timing Delay

- Self-capacitances dominate

■ Signal Integrity

- "Noise" or "Crosstalk"
- Cross-capacitances dominate

■ AutoIC generates **lumped** RC models

- Extracts high-accuracy 3D self-caps and cross-caps from the interconnect layout
- 3D visualization identifies areas for correction

■ AutoNet generates **distributed** RC models

- Important differences between lumped and distributed simulations

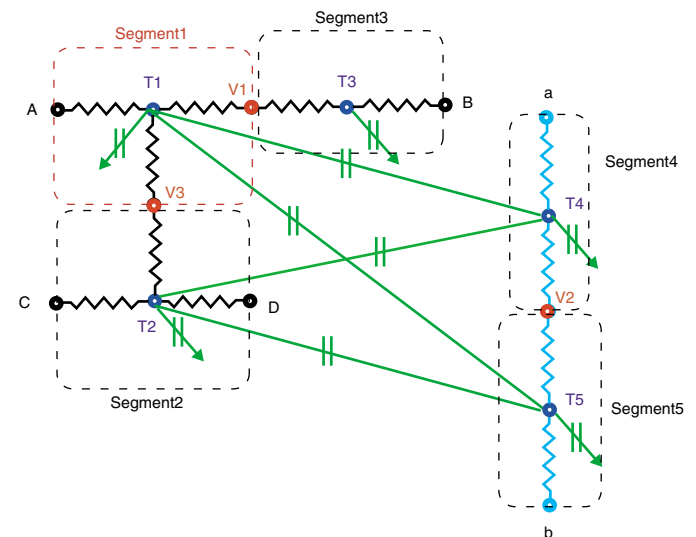
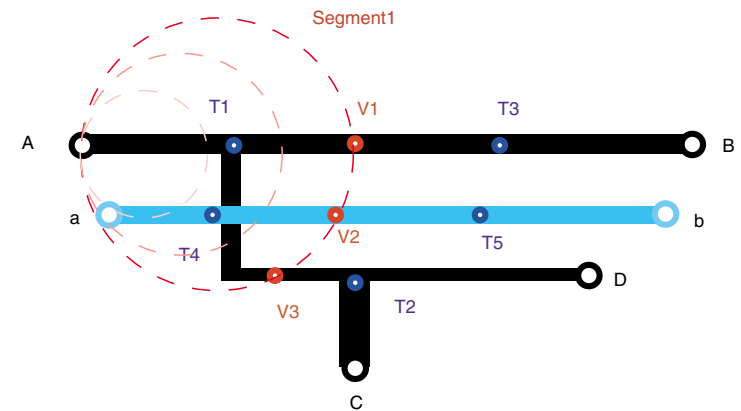
■ Go from Layout to Distributed Spice

■ Variable model size

- Lumped net = 1 segment
- Distributed net = multiple segments

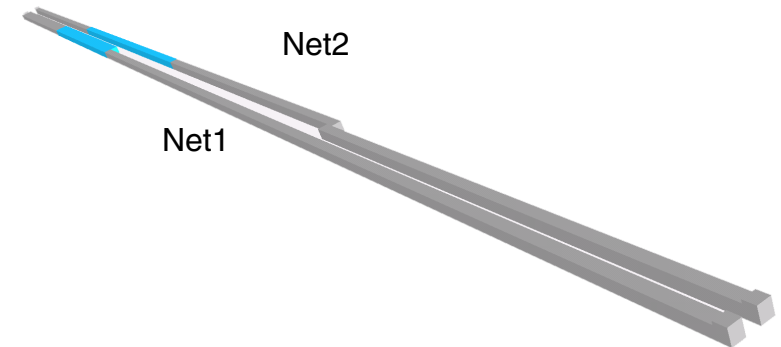
■ Segments

- Spice star-model for each segment
- Created from layout
- Cross-caps between segments
- Compact Spice model size
- No model reduction needed



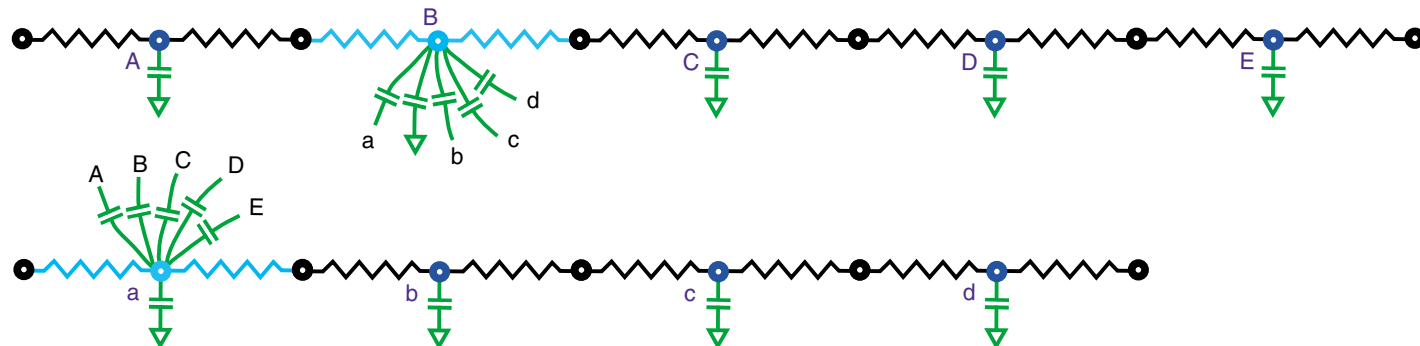
■ Automatic segmentation

- 5 segments on Net1
- 4 segments on Net2



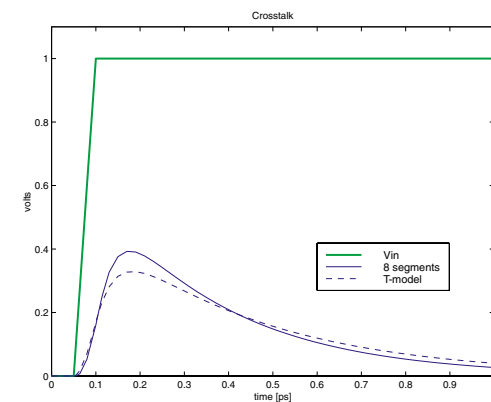
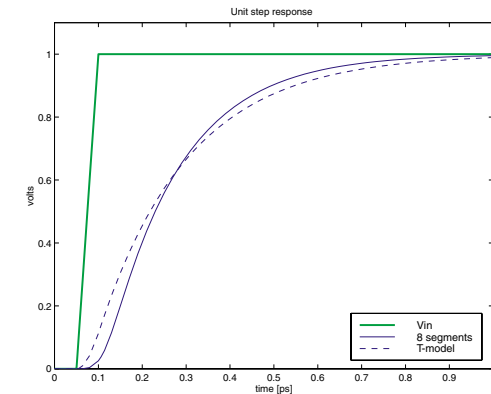
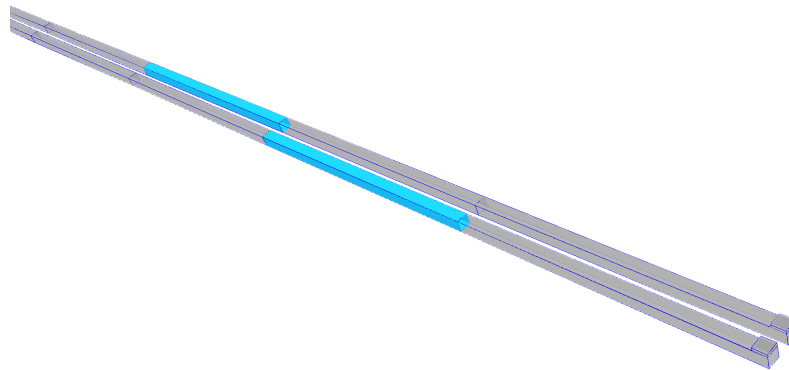
■ Distributed RC spice model

- Each segment has self-capacitance
- Each segment has cross-capacitances to segments on other nets



■ Parallel bus lines

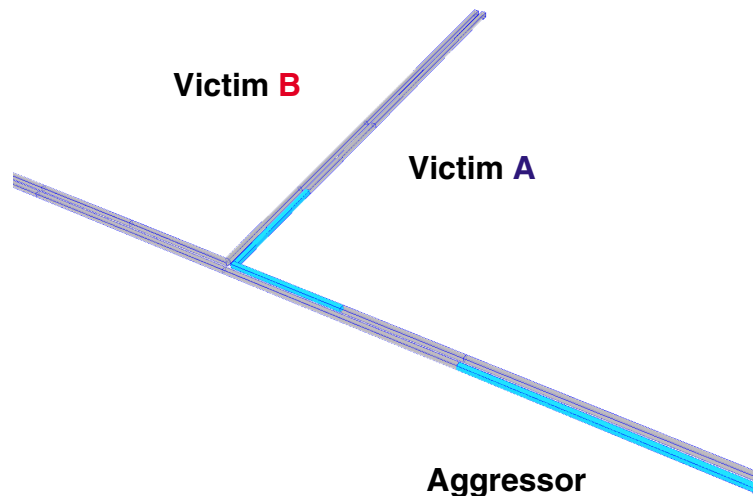
- Generated distributed model (8 segments per net)
- Generated lumped T-model (1 segment per net)



- **Step Response**
 - Distributed and T model responses similar
- **Coupling**
 - Distributed and lumped responses similar

■ Non-uniform bus lines

- Generated distributed model (4-5 segments per net)
- Generated lumped T-model (1 segment per net)

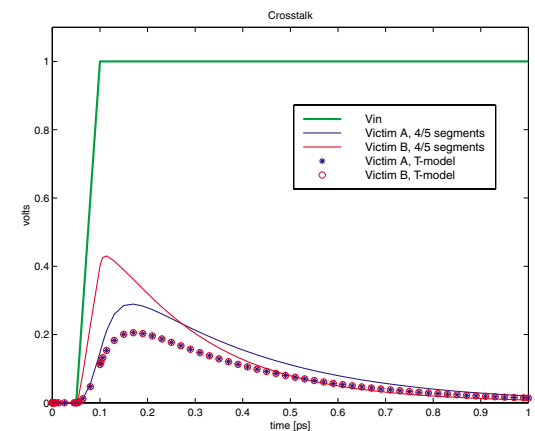
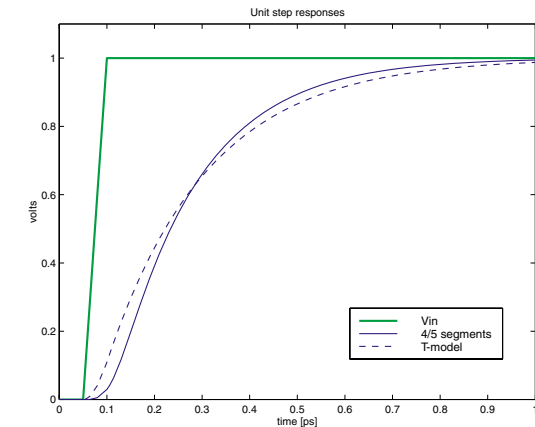


● Step Response

- Distributed and T model responses similar

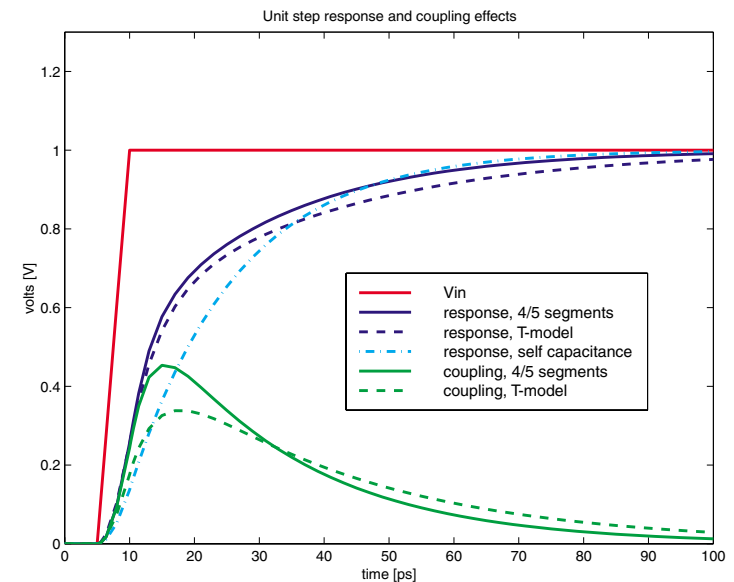
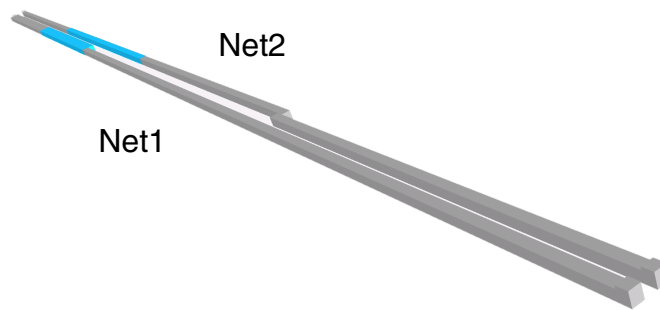
● Coupling

- 2x more noise on distributed model



■ Parallel lines with varying cross-section

- Net1 switches



- Step Response

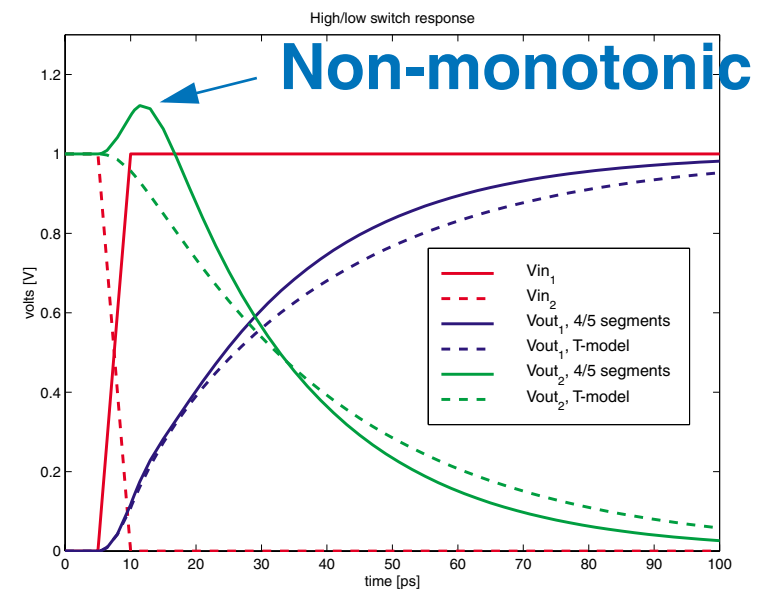
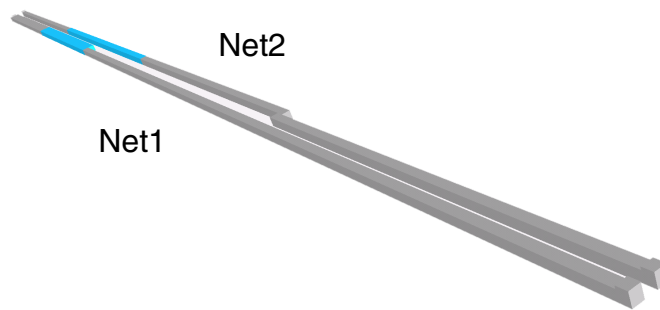
- Distributed and T models similar
- Commonly used self-cap model is inaccurate

- Coupling

- 30% larger noise with distributed model

■ Non-uniform parallel lines

- Nets switch in opposite directions



- **Step Response**

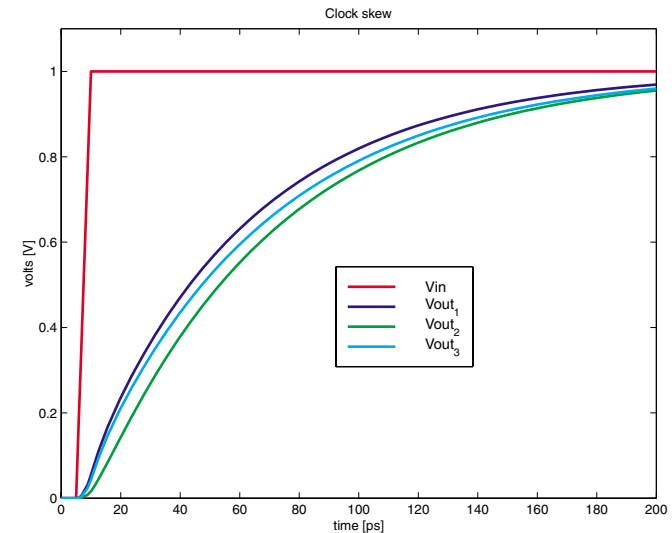
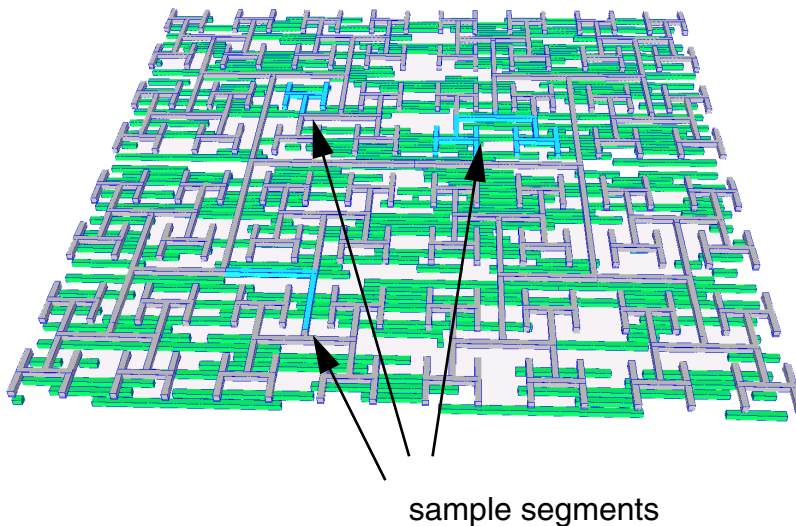
- Distributed and T models similar

- **Coupling**

- Distributed model shows non-monotonic behavior

■ Clock Tree Skew

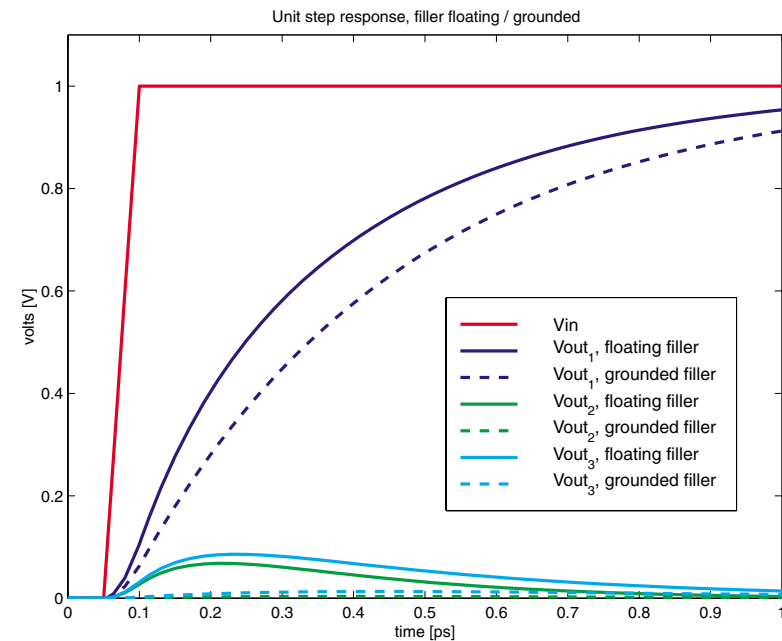
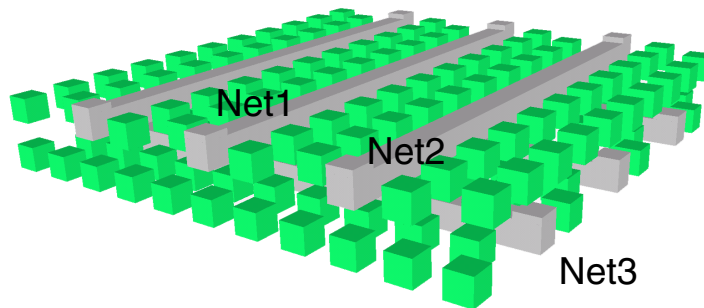
- Hierarchical H-shaped layout
- 256 terminals



- RC model with 70 segments
- Non-constant clock skew due to cross capacitances
- **20% clock skew at 3 random clock terminals!**

■ Compare Floating Filler & Grounded Filler

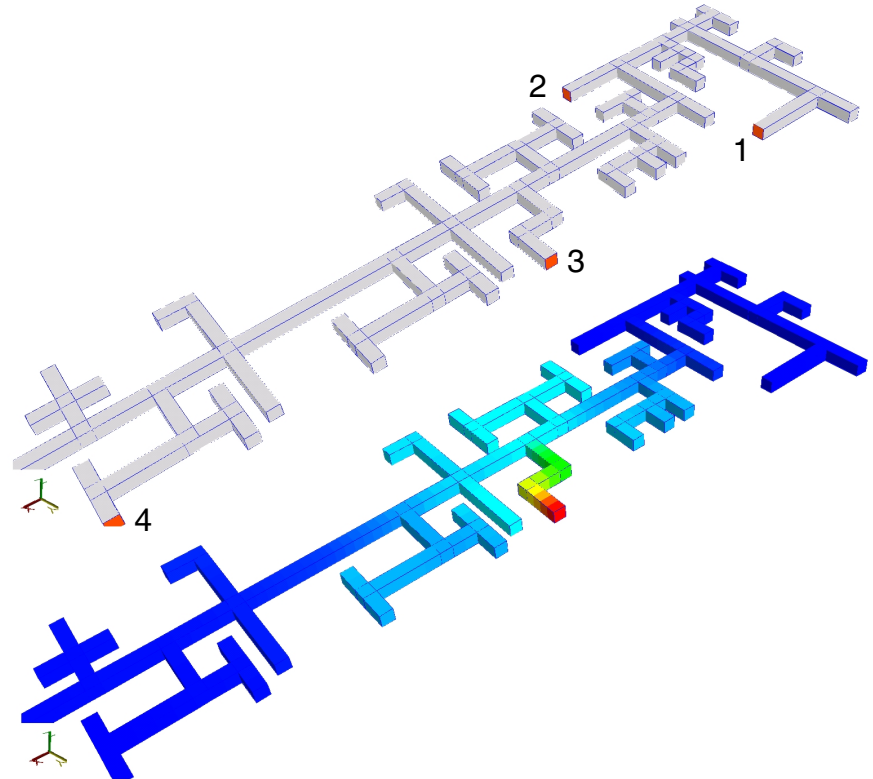
- 3x3 crossing bus
- Net1 switches



■ Significant filler problem

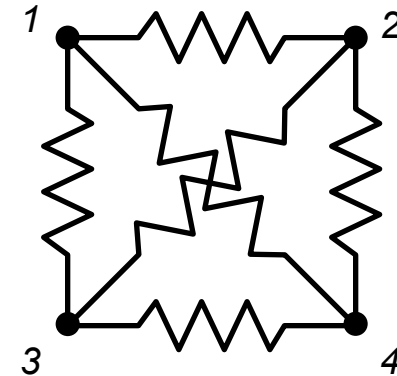
- 25% difference in risetime
- 9x increase in noise level

- AutoIC solves 3D field **outside** interconnects
- AutoRdrop solves 2D/3D field **inside** interconnects
 - Varying angles, width, cross-section
 - Vias
 - Aluminum, copper
 - Current sink/source
- 2D/3D Field Solver
 - Solves potential drop
 - Resistance
 - Solves current density through wire
 - Enables electromigration analysis



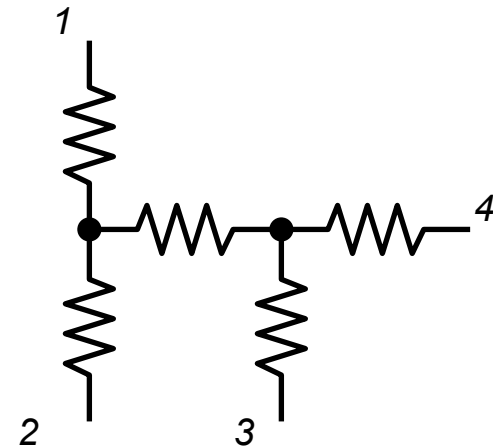
■ "Naive" Resistance Network

- N-ports require N simulations, resulting in N^2 resistances



■ "Smart" Resistance Network

- N-ports require N simulations, resulting in N resistances



■ Field Simulation

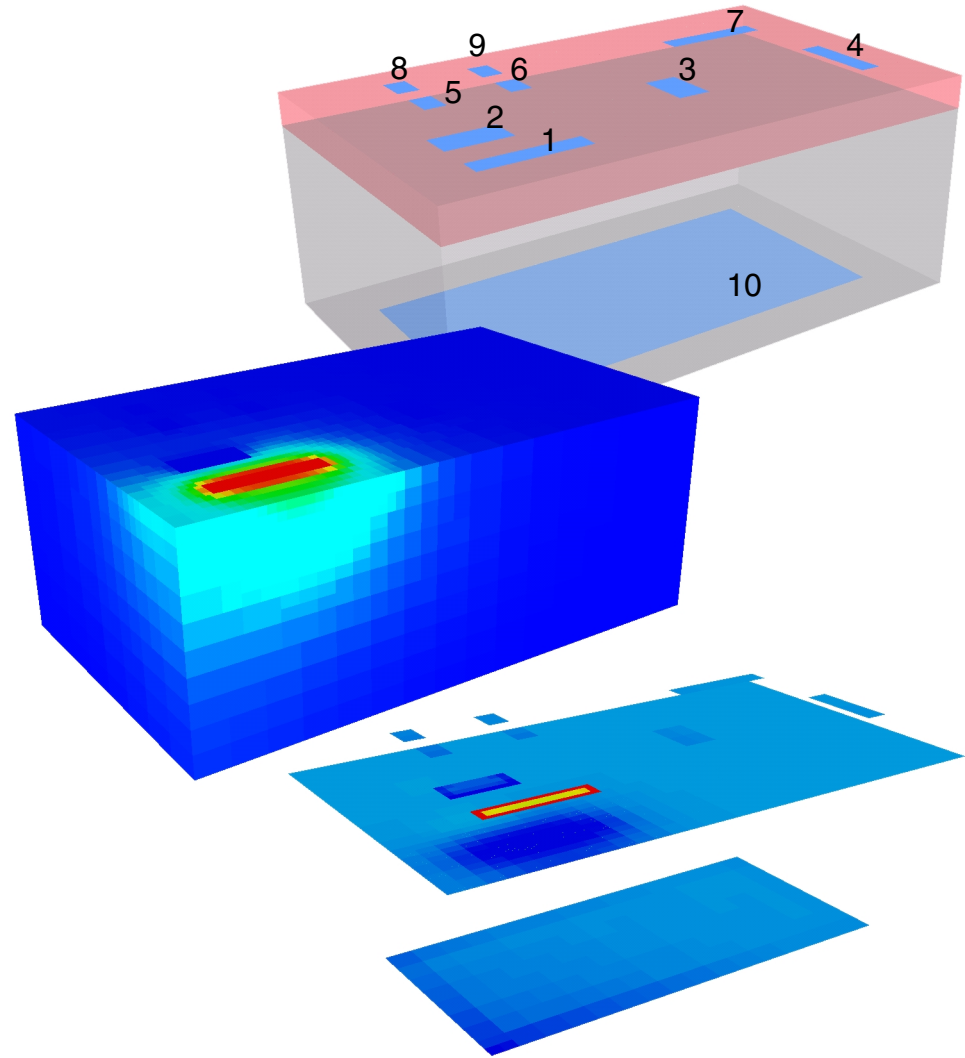
- 2D resistance is very accurate, much faster than 3D
- 2D suitable for resistance, 3D suitable for capacitance

- Solves 3D field inside substrates

- Contacts
- Multiple materials

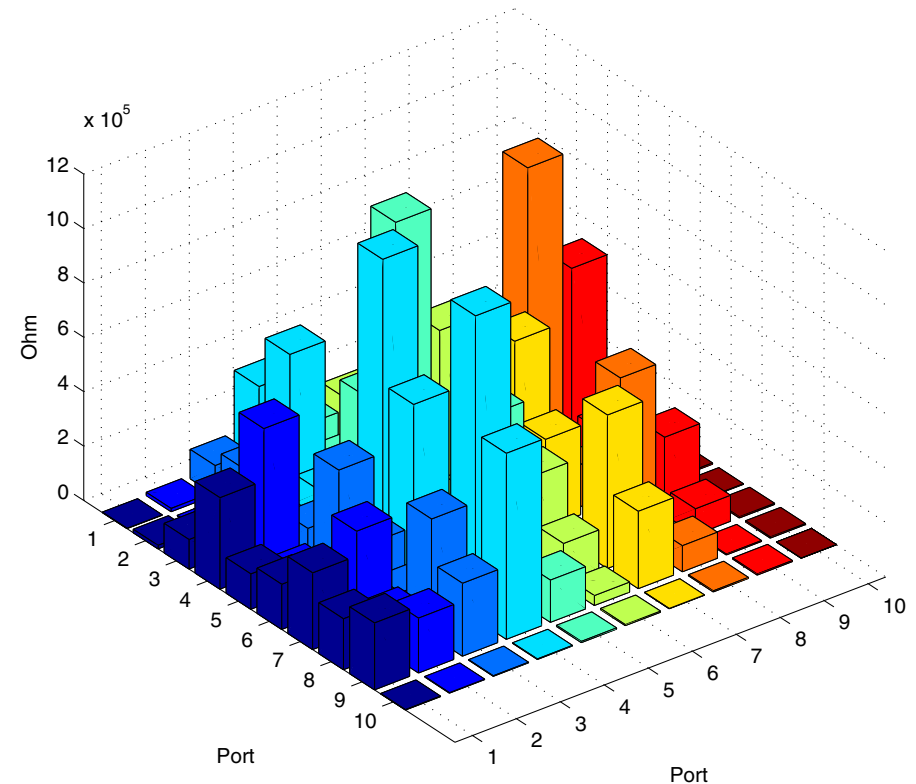
- 3D Field Solver

- Solves potential distribution
- Solves electrostatic flux distribution
- Solves current density through contacts



■ Resistance Network

- Resistance calculated from calculated current densities
- Resistor for every port-port interaction
- Automatic spice model



Shipping Now



- **Fastest, Most accurate, Easiest to use**

- Replace multiple tools
- Large engineering time savings

- **Licenses**

- End-user licenses
- OEM, Embedded licenses

- **Available Now**

- Sun, Linux, HP platforms
- Uniprocessor & SMP configurations

For More Information



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